

Notice of References Cited	Application/Control No. 09/683,020	Applicant(s)/Patent Under Reexamination GOEBEL, KAI FRANK	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0183986 A1	12-2002	Stewart et al.	703/2
	B	US-2002/0128805 A1	09-2002	Goldman et al.	703/2
	C	US-6,725,112 B1	04-2004	Kaminsky et al.	700/97
	D	US-6,604,092 B1	08-2003	Stewart, Lisa Ellen	706/47
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	"Conducting Experiments With Experiment Manager", M. Angel, pp. 535-541, Proceedings 1996 Winter Simulation Conference ACM 1996				
	V	"Design-Ease Software Version 6 User's Guide" Stat-Ease Inc. Copyright 2000				
	W	"Designing Simulation Experiments: Taguchi Methods and Response Surface Metamodels", Ramsberg et al, Proceedings 1991 Winter Simulation Conference, pp 167-176, ACM 1991				
	X	"Regression Metamodels and Design of Experiments", van Groenendall et al, Proceedings 1996 Winter Simulation Conference, pp 1433-1439, ACM 1996				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Process Optimization Using Design of Experiments", Porter et al, Pharmaceutical Technology, October 1997
	V	"Validation of Models: Statistical Techniques and Data Availability", Kleijnen, Proceedings 1999 Winter Simulation Conference, pp. 647-654, ACM 1999
	W	"Systems for Monte Carlo Work", Grier, Proceedings 1987 Winter Simulation Conference, pp. 428-433, ACM 1987
	X	"Design of Experiments in BDD Variable Ordering: Lessons Learned", Harlow et al, ICCADA 98', pp. 646-652, ACM 1998

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Leveraging the Design Chain", White Paper, ANSYS Inc. 2002
	V	"Design-Ease Software, Version 6.0, Product Specification, 2001
	W	"State of Mathematical Modeling and Simulation in the Finnish Process Industry, Universities and Research Centres", Klemola et al, Technology Review 2001
	X	

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.